

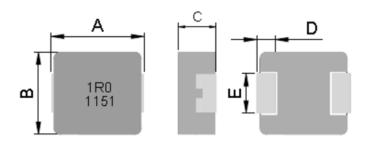
FEATRLRES

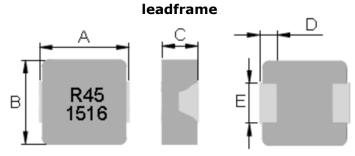
- Carbonyl Powder.
- Compact design.
- High current , low DCR , high efficiency.
- Very low acoustic noise and very low leakage flux noise.
- High reliability.
- 100% Lead(Pb)-Free and RoHS compliant.

APPLICATIONS

- Note PC power system, incl. IMVP-6
- DC/DC converter .

CONFIGRLRATIONS & DIMENSIONS (unit in mm)

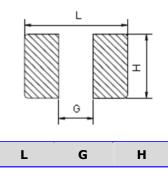




non-leadframe

Туре	A	В	С	D	E
HMPL1004H	11.0±0.5	10.0±0.3	3.8±0.2	2.3±0.3	3.0±0.3

Recommended Land pattern



L	G	н
13.6	5.4	3.5

Note:

- 1. The above PCB layout reference only.
- 2. Recommend solder paste thickness at 0.12mm and above.



ELECTRICAL CHARACTERISTICS

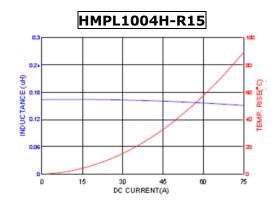
Daub Normalian	Inductance L0	I rmc (A) Turn	Look (A) Turn	$DCR(m\Omega)$	$DCR(m\Omega)$	Time
Part Number	(uH)±20% @ 0 A	1 rms (A) Typ.	I sat (A) Typ.	Typ.@25 ℃	Max.@25℃	Туре
HMPL1004H-R15YG-D	0.15±30%	43	75	0.5	0.6	non-leadframe
HMPL1004H-R18YG-D	0.18±30%	38	72	0.54	0.8	non-leadframe
HMPL1004H-R20YG-D	0.20±30%	35	70	0.66	0.95	non-leadframe
HMPL1004H-R22MG-D	0.22	35	60	0.8	1.0	non-leadframe
HMPL1004H-R27MG-D	0.27	33	60	0.82	1.0	non-leadframe
HMPL1004H-R30MG-D	0.30	32	60	0.94	1.1	non-leadframe
HMPL1004H-R33MG-D	0.33	31	60	1.00	1.2	non-leadframe
HMPL1004H-R36MG-D	0.36	31	60	1.05	1.2	non-leadframe
HMPL1004H-R39MG-D	0.39	30	60	1.1	1.3	non-leadframe
HMPL1004H-R45MG-D	0.45	29	45	1.3	1.5	non-leadframe
HMPL1004H-R47MG-D	0.47	28	43	1.3	1.5	non-leadframe
HMPL1004H-R56MG-D	0.56	25	40	1.6	1.8	non-leadframe
HMPL1004H-R68MG-D	0.68	22	39	2.4	2.7	non-leadframe
HMPL1004H-R75MG-D	0.75	22	39	2.4	2.7	non-leadframe
HMPL1004H-1R0MG-D	1.00	18	36	3.0	3.3	non-leadframe
HMPL1004H-1R2MG-D	1.20	17	33	3.3	3.8	non-leadframe
HMPL1004H-1R5MG-D	1.50	16	33	4.0	4.6	non-leadframe
HMPL1004H-2R2MG-D	2.20	12	27	6.5	7.0	leadframe
HMPL1004H-2R5MG-D	2.50	11.5	23	7.9	8.7	leadframe
HMPL1004H-3R3MG-D	3.30	11	20	10.8	11.8	leadframe
HMPL1004H-4R0MG-D	4.00	10.2	18	13	15	leadframe
HMPL1004H-4R7MG-D	4.70	10	17	15.0	15.5	leadframe
HMPL1004H-5R6MG-D	5.60	9.0	14	17	19.3	leadframe
HMPL1004H-6R8MG-D	6.80	8.5	13.5	17.5	23.3	leadframe
HMPL1004H-8R2MG-D	8.20	8.0	12.5	20	22.5	leadframe
HMPL1004H-100MG-D	10.0	7.5	12.0	27.0	30	leadframe
HMPL1004H-150MG-D	15.0	6.25	10	40	45	leadframe
HMPL1004H-220MG-D	22.0	5.0	7.0	64	74	leadframe
HMPL1004H-270MG-D	27.0	4.0	6.0	86	100	leadframe
HMPL1004H-330MG-D	33.0	3.5	5.0	92	112	leadframe
HMPL1004H-470MG-D	47.0	3.0	4.5	145	167	leadframe
HMPL1004H-680MG-D	68.0	2.0	3.0	205	240	leadframe
HMPL1004H-820MG-D	82.0	1.5	2.5	265	320	leadframe

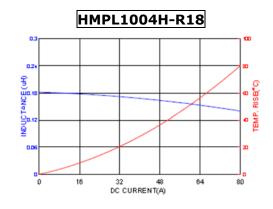
Note:

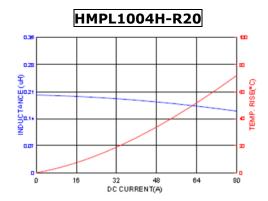
- 1.Test frequency : Ls : 100KHz /1.0V. 2.All test data referenced to 25° C ambient.
- 3.Testing Instrument(or equ): L: HP4284A,CH11025,CH3302,CH1320,CH1320S LCR METER / Rdc:CH16502,Agilent33420A MICRO OHMMETER.
- 4.Heat Rated Current (Irms) will cause the coil temperature rise approximately ΔT of 40°C
- 5. Saturation Current (Isat) will cause L0 to drop approximately 20%.
- 6.The part temperature (ambient + temp rise) should not exceed 125° Cunder worst case operating conditions. Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application.
- 7. Special inquiries besides the above common used types can be met on your requirement.

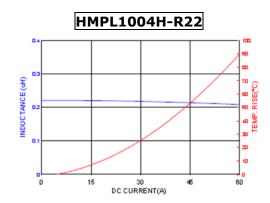


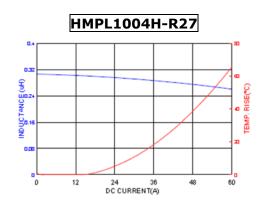
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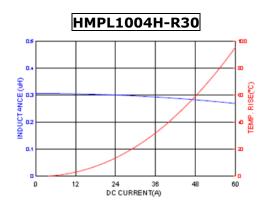


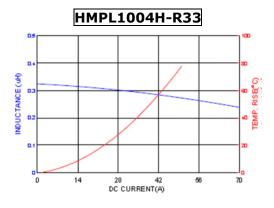


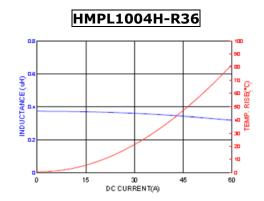




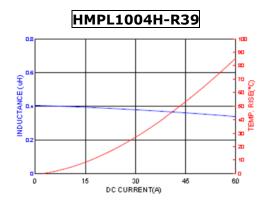


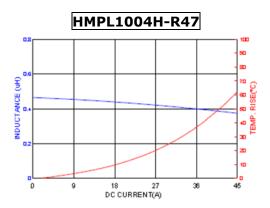


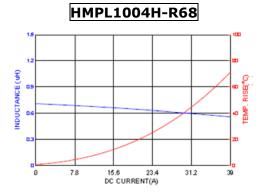


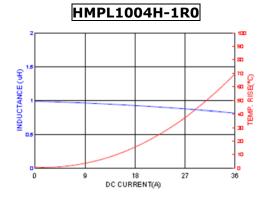


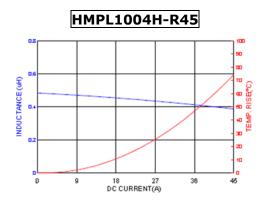


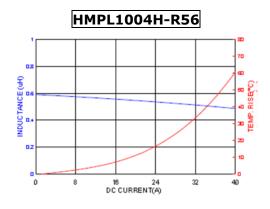


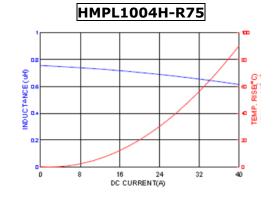


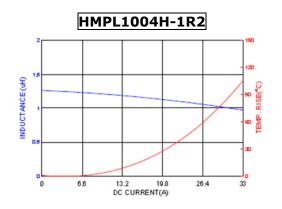




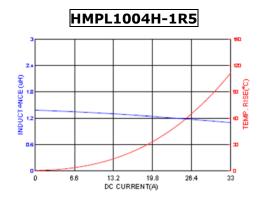


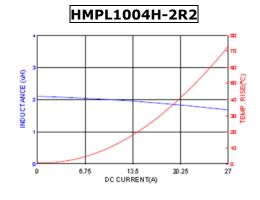


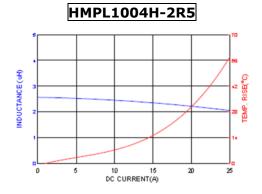


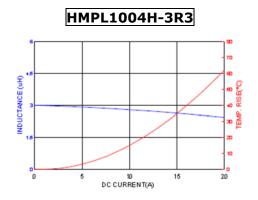


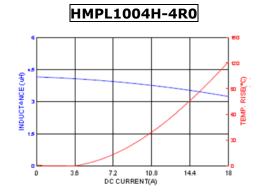


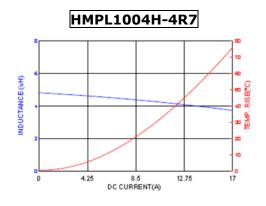


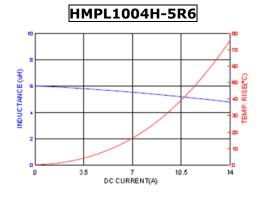


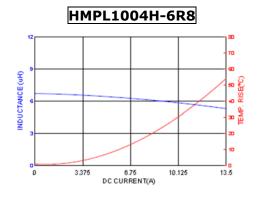




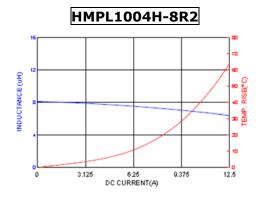


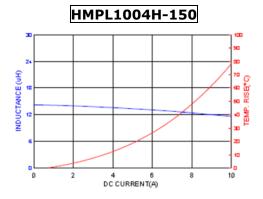


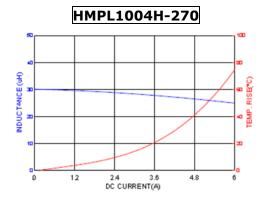


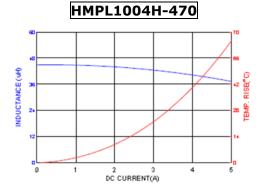


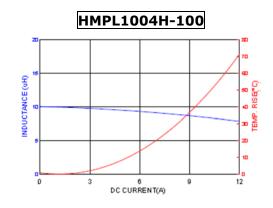


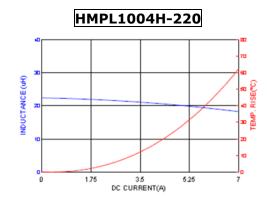


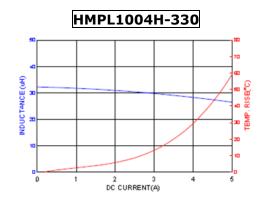


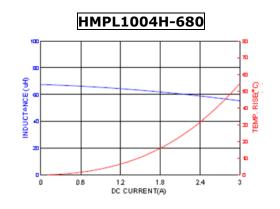




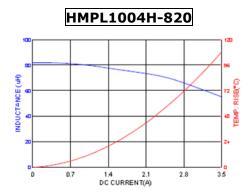












Reliability and Test Condition

Item	Performance	Test Condition
Operating temperature	-40~+125℃ (Including self - temperature rise)	
Storage temperature	110~+40°C,50~60%RH (Product with taping) 240~+125°C (on board)	
Electrical Performance Test		
Inductance	Refer to standard electrical characteristics list.	HP4284A,CH11025,CH3302,CH1320,CH1320S LCR Meter.
DCR	Refer to standard electrical characteristics list.	CH16502,Agilent33420A Micro-Ohm Meter.
Saturation Current (Isat)	Approximately△L30%	Saturation DC Current (Isat) will cause L0 to drop $\triangle L(\%)$
Heat Rated Current (Irms)	Approximately △T40°C	Heat Rated Current (Irms) will cause the coil temperature rise $\triangle T(\mathbb{C})$. 1.Applied the allowed DC current 2.Temperature measured by digital surface thermometer
Reliability Test		
Life Test		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles) Temperature: 125±2°C (Inductor) Applied current: rated current Duration: 1000±12hrs Measured at room temperature after placing for 24±2 hrs
Load Humidity		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity: 85±2 * R.H, Temperature: 85°C±2°C Duration: 1000hrs Min. with 100% rated current Measured at room temperature after placing for 24±2 hrs
Moisture Resistance	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles 1. Baked at50℃ for 25hrs, measured at room temperature after placing for 4 hrs. 2. Raise temperature to 65±2℃ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25℃ in 2.5hrs. 3. Raise temperature to 65±2℃ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25℃ in 2.5hrs,keep at 25℃ for 2 hrs then keep at -10℃ for 3 hrs 4. Keep at 25℃ 80-100%RH for 15min and vibrate at the frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1~2 hrs.
Thermal shock		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -40±2°C 30±5min Step2: 25±2°C ≤0.5min Step3: 125±2°C 30±5min Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs



		Ossillation Fraguency: 10 2K 10Hz for 20 minutes
Vibration		Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes Equipment: Vibration checker
		Total Amplitude:1.52mm±10%
		Testing Time: 12 hours(20 minutes, 12 cycles each of 3
		orientations),
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805 inch(2012mm):40x100x1.2mm <0805 inch(2012mm):40x100x0.8mm Bending depth: >=0805 inch(2012mm):1.2mm <0805 inch(2012mm):0.8mm duration of 10 sec.
Shock	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value.	Type Value duration (D) Wave change (Vi)ft/sec
Citati	RDC: within ±15% of initial value and shall not	SMD 50 11 Half-sine 11.3
	exceed the specification value	Lead 50 11 Half-sine 11.3
Solder ability	More than 95% of the terminal electrode should be covered with solder.	Preheat: 150°C,60sec.∘ Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5°C ∘ Flux for lead free: Rosin. 9.5% ∘ Dip time: 4±1sec ∘ Depth: completely cover the termination Depth: completely cover the termination
Resistance to Soldering Heat		Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate heat cycles
		260 ±5 (solder temp) 10 ±1 25mm/s ±6 mm/s 1
Terminal Strength	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value e	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STE 020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tester apply a force(>0805:18g, <=0805:0.5kg)to the side of a device bein tested. This force shall be applied for 60 +1 seconds. Also the force sha be applied gradually as not to apply a shock to the component bein tested.

Note : When there are questions concerning measurement result : measurement shall be made after 48 ± 2 hours of recovery under the standard condition.